

TR SCAN



TR SCAN

INTRODUCTION

The TR Scan offers an innovative alternative to classical surface measurement. Its modular concept, allowing adaptation to each application, and its simple use, make it very efficient in the workshop. Because of its simplicity of use, the TR Scan can be operated by workshop personnel to get reliable results secured with minimum training. All measured surfaces can be treated according to current international standards such as ISO, DIN, JIS, ASME, CNOMO etc., as well as the upcoming ISO 25178 3D standard.

The TR Scan is completely designed and manufactured in Switzerland according to the highest quality standards. Robustness, reliability and longevity are part of our tradition. Trimos instruments have been used in workshops and labs for over 30 years.

The interchangeability of the measuring heads gives the possibility to select the most appropriate technology for each application. This flexibility allows the characterization of surfaces in numerous application fields, such as mechanical industry (all types of machined surfaces), car and aerospace industries, photovoltaics, as well as plastics, papers, imprints, fibrous materials, wood, abrasives, paint, cosmetics, etc.

MEASURING RESULTS FULLY COMPARABLE TO CLASSICAL SYSTEMS

COMPLIES TO ALL INTERNATIONAL STANDARDS

INTUITIVE, EASY TO USE INTERFACE

ROBUST INDUSTRIAL SYSTEM FOR THE WORKSHOP

POSSIBLE AUTOMATED MEASUREMENTS

MODULAR AND COMPACT CONCEPT

MEASUREMENT AND ANALYSIS WITHIN SECONDS



DESCRIPTION

AUTOMATED Z-AXIS

Motorized axis allow for precise and automated measurements. The working distance is automatically worked out by the system.



INTERCHANGEABLE MEASURING HEADS

The unique system of interchangeable measuring heads confers a high degree of adaptability to every application. Changing a head is quickly done and automatically recognized by the system. Several technologies are available for complete application coverage.

TRIMOS NANOWARE MEASURE

Software for the management of all measurement parameters

TRIMOS NANOWARE ANALYSIS

Software for the analysis of measured surfaces



TR SCAN

DISPLAY/SOFTWARE

TRIMOS NANOWARE MEASURE

This exclusive software allows the handling of the instrument (positioning and configuration of all measurements).

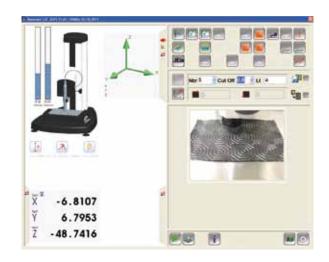
Positioning in X,Y,Z is performed either automatically by predefined parameters or via the use of an intuitive joystick aided by a integrated positioning laser and a camera (optional).

Once positioned, measurements are taken automatically with one click or via the use of a manual size parameter in a few seconds.

INTUITIVE POSITIONING

INSTANT MEASUREMENT

PROGRAMMABLE MEASUREMENTS WITH PICTURE



TRIMOS NANOWARE ANALYSIS

This software allows the analysis of all measured surfaces according to current international standards such as ISO, DIN, JIS, ASME, CNOMO etc., as well as the 3D standard ISO 25178.

Analysis can be performed automatically by the use of a template, or the user can have direct access to the raw data. The incorporated analysis software is powered by Mountains®, the most powerful and recognized 2D/3D surface analysis software available.

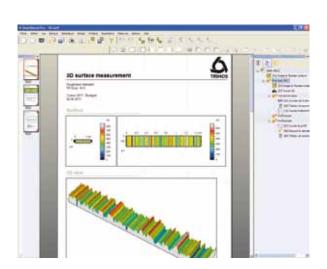
Reports are automatically generated during analysis. Any report can be used as a template later.

POWERFUL ANALYSIS

PROFESSIONAL REPORTING

SUITABLE MODULE FOR EACH APPLICATION NEED

COMPLIES TO ALL INTERNATIONAL STANDARDS



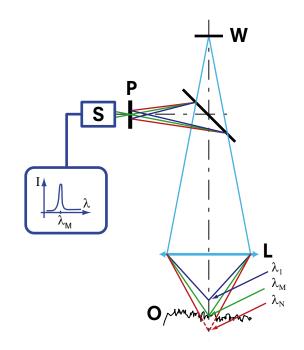




THE CCM TECHNOLOGY

Chromatic Confocal Microscopy (CCM) has been acknowledged worldwide as an accurate and reliable technique for non-contact surface measurement. A chromatic lens L generates the image of a point white-light source W as a continuum of monochromatic images located on the optical axis ("Chromatic coding"). A sample O is located inside the color-coded segment and its surface scatters the incident light beam. The backscattered light passes through the chromatic lens L in the opposite direction, and arrives at a pinhole P which filters out all wavelengths except a single wavelength, λM . The collected light is analysed by a spectrometer S. The sample position is directly related to the detected wavelength.

- High resolution
- Works on all types of sample materials
- · Wide choice of measuring ranges
- Steep slope compatibility
- Coaxial (no shadowing)
- Recognised method by ISO 25178



CCM P1 MEASURING HEAD



CCM-P1 (support & spectrometer)

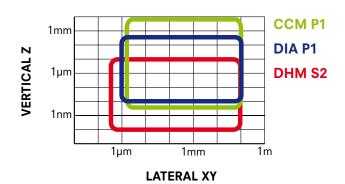


TA-MI-701 ÷ 713 Optical pen

COMPLEMENTARY TECHNOLOGIES

There is no universal technology for surface measurement. The modularity of the TR Scan allows the use of the best adapted head for each application.

The diagram here below shows the application field of the TR Scan and of its various measuring heads according to the material structure.



TR SCAN

MEASURING HEADS

DHM S1 & S2

DHM Technology:

- Smooth, grinded and polished surfaces
- Steel, aluminium, titanium, silicon, gold, ceramics, glass
- High precision and speed, 2D/3D

CCM P1

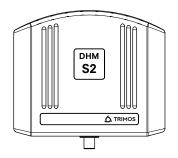
Chromatic Confocal Technology:

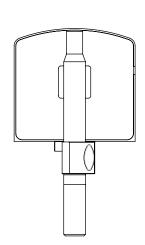
- Machined and rough surfaces, micro-structures
- Metals, plastics, abrasives, papers, textiles, cosmetics
- Large vertical range, all materials, 2D/3D

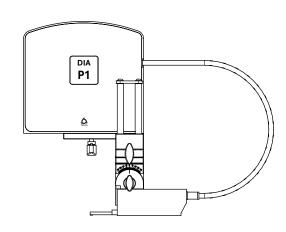
DIA P1

Diamond Stylus Tip Technology:

- Roughness measurement with contact
- Classical roughness measurements (2D)
- Internal measurements







TECHNICAL SPECIFICATIONS

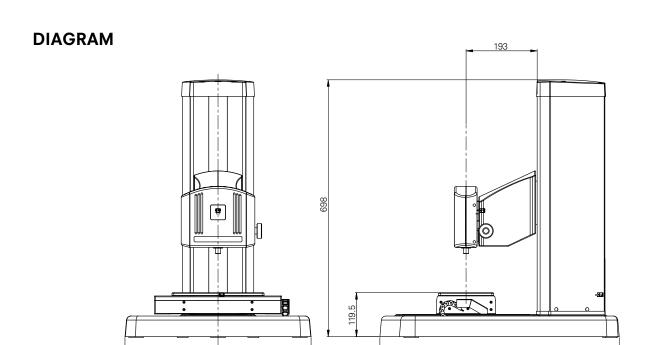
| TR Scan | | 101 | 201 | 301 |
|---------------------------------|----|-----|-----|-----|
| Horizontal measuring range X | mm | - | 100 | 100 |
| Horizontal measuring range Y | mm | - | - | 100 |
| Vertical measuring range Z | mm | | 240 | |
| Measuring system resolution XYZ | μm | | 0.1 | |
| Positioning accuracy XYZ | μm | | 1 | |
| Rectitude of the guideways XY | μm | | 1.5 | |
| Max weight of the part | kg | | 20 | |

| Measuring heads | | DHM S1 | DHM S2 | CCM P1 | DIA P1 |
|-------------------------------------|----|-------------|-------------|-----------------------|--------|
| Vertical resolution (Z) | nm | 1 | 1 | 8 ÷ 22 ²⁾ | 10 |
| Lateral resolution (XY) | μm | 0.6 | 0.6 | $0.9 \div 3.5^{2}$ | 1 |
| Typical measuring range Ra 1) | μm | 0.4 | 1.6 | >200 2) | 20 |
| Vertical measuring range 1) | μm | 3 | 7 | $130 \div 400^{2}$ | 350 |
| Max. permissible errors Ra | % | 1% | 1% | 1% ÷ 5% ²⁾ | 5% |
| Repeatability (Ra, 1 ₀) | nm | < 0.1 | < 0.1 | $<5 \div 20^{2}$ | 9 |
| Sample reflectivity | % | < 1% ÷ 100% | < 1% ÷ 100% | 1% ÷ 100% | - |
| Field of view | mm | 0.25 x 0.25 | 0.25 X 0.25 | - | - |

¹⁾ Values may differ depending on the surface texture

²⁾ Objective dependent





STANDARD INSTRUMENT

The TR Scan instruments are supplied as follows:

Instrument according to specification (without measuring head)

1 measuring head (DHM S1, DHM S2, CCM P1+TA-MI-701/TA-MI-708)

PC with 1 TFT screen

Nanoware Measure and Nanoware Analysis software (according to selected model)

User's manual (750 50 0028 03)

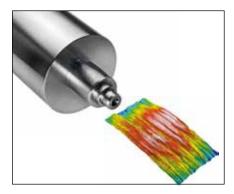
CODE NUMBER

| TR Scan | Purpose | Meas. head | Axes | Software |
|--------------------------------|---|------------|--|----------------------------------|
| TRS201CCM 700 405 20 11 | Non-contact profiles measurements 2D | CCM P1 | - 1 vertical axis Z - 1 horizontal axis X | Nanoware LT (2D analysis) |
| TRS201DHM 700 405 20 21 | Extended profiles measurements 3D, metallic parts | DHM S2 | - 1 vertical axis Z - 1 horizontal axis X | Nanoware STT (2D/3D analysis) |
| TRS301DHM 700 405 30 11 | 3D measurements, metallic parts | DHM S2 | 1 vertical axis Z2 horizontal axes XY | Nanoware STT (2D/3D analysis) |

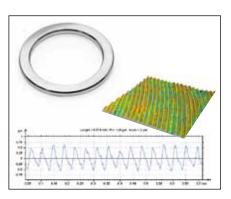
The TR Scan can also be specifically equipped according to the needs for each application (head(s) and measuring table, software). An exhaustive list of equipments can be found in the accessories section.

TR SCAN

APPLICATIONS



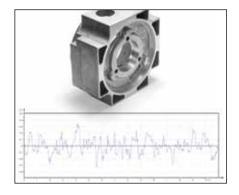
Surface spinning measurement on a steel printing roll (DHM S2)



Verification of an aluminium ring joint gasket for the aircraft industry (DHM S2)



Texture analysis of a chemically polished titanium surface (DHM S2)



Classical 2D internal roughness measurement (DIA P1)





Interchangeable Measuring Heads

The unique system of interchangeable measuring heads confers a high degree of adaptability to every application. Changing a head is quick and automatically recognized by the system. Several technologies are available for complete application coverage.



A. Automated Z-Axis and Modular Measuring Table

Motorized X, Y, Z axes allow for precise and automated measurements. It includes the ability to image large areas by the use of stitching and the convenience of automatic working distance detection. The modularity of the X or XY sample stage offers a high degree of customization based on application.

B. No special skills needed

Trimos Nanoware allows for measurements to be taken automatically, using predefined parameters, or manually with only the input of the measurement size. Reports can be generated with one touch through the use of predefined parameters and analysis templates, eliminating the need for specialized training and measurement errors.

Highly Flexible System

The Trimos TR Scan is a flexible and universal surface texture measurement system focusing on Digital Holographic Imaging Technology. No other tool can compare to its combined speed, resolution, ease of use and flexibility. Its automated and modular design allow for a high degree of customization based on application's needs and increased functionality with integrated stitching and profilometer compatibility.

Due to its simplicity, the TR Scan can be operated by workshop personnel and reliable results secured with minimum training.

All measured surfaces can be treated according to current international standards such as ISO, DIN, JIS, ASME, CNOMO etc., as well as the upcoming ISO 25178 3D standard.

The TR Scan is completely designed and manufactured in Switzerland according to the highest quality standards. Robustness reliability and longevity is our tradition. Trimos instruments have been used in workshops and labs for over 30 years.



2.

QUICK AND EFFICIENT MEASUREMENTS



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Powerful Analysis

Analysis can be performed automatically by the use of a template or the user can have direct access to the raw data. The incorporated analysis software is powered by Mountains®, the most powerful and recognized 2D/3D surface analysis software available.

Professional Reporting

Reports are automatically generated during analysis. Any report can be used as a template later.

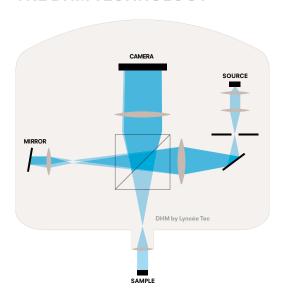
Intuitive Positioning

Positioning in X,Y,Z is performed either automatically by predefined parameters or via the use of an intuitive joystick aided by a integrated positioning laser and a camera (optional).

Instant Measurement

Once positioned, measurements are taken automatically with one click or via the use of a manual size parameter in a few seconds. 3.

THE DHM TECHNOLOGY





DHM® (Digital Holographic Microscopy) is a non-contact surface measurement technology originally developed for the biotech and medical industry. DHM generates a high-resolution 3D digital image of a sample using the principle of holography. A hologram generated by combining a coherent reference wave with the wave received from a sample is recorded by a CCD camera and transmitted to a computer for numerical reconstruction.

A single hologram is acquired in a few microseconds, making the whole system insensitive to vibrations. Software procedures allows computation of the complete wavefront emanating from an object and provides:

- Intensity images providing the same contrast as with classical optical microscopy
- Phase images providing quantitative data, defined at a sub-wavelength scale, used for accurate and stable 3D measurements.

The phase image reveals the surface topography with a sub-nanometric vertical resolution. This digital approach to holography allows the application of computer-based procedures at a level never reached in optical microscopy so far. In particular the DHM principle features software compensation of optical aberrations, digital image focusing and numerical compensation for sample tilt and environmental disturbances, making DHM instruments robust and easy to use for routine inspections at the nanometer and micrometer scale. DHM is used exclusively by Trimos for surface texture measurement. This technology has numerous advantages compared to other contact and non-contact measurement technologies: in particular extremely fast measurements, high resolution, simple working process no moving parts and no requirement for special environmental conditions.

- Acquisition in a few microseconds
- Vibration incensitive
- High image quality
- Subnanometric resolution
- No moving parts
- No requirement for special environmental conditions

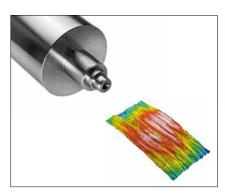
DHM is a recognized surface texture measurement method according to the standard ISO 25178-6.

4.

APPLICATIONS VERSATILITY

The TR Scan provides rapid, reliable and accurate surface texture characterization for a large application range and materials such as steel, aluminum, brass, titanium, silicon, gold, ceramics, glass etc. The system can be tailored to fit the requirements of many industries:

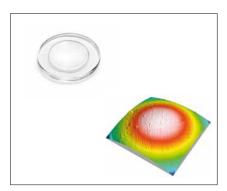
- Automotive
- Aircraft
- Machine Tool
- Watch
- Printing
- Railway
- RailwayBearing
- Medical
- Materials
- Optics
- Forensic
- Photovoltaic
- MEMS
- Semiconductor
- Electronic



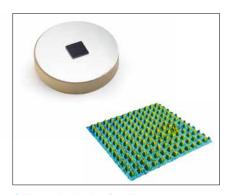
Steel Surface spinning measurement on a printing roll (DHM S2)



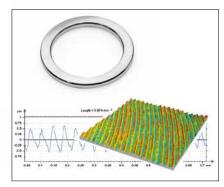
Titanium Texture analysis of a chemically polished surface (DHM S2)



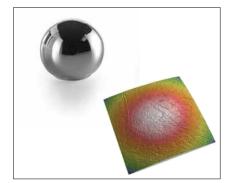
Glass Roughness inspection of micro lenses (DHM S2)



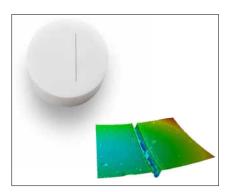
Silicon Analysis of a silicon microstructure (DHM S2)



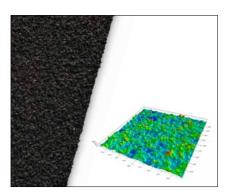
Aluminium Verification of a ring type joint gasket for the aircraft industry (DHM S2)



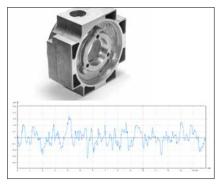
Cobalt-chromium Quality control of a polished prosthesis surface (DHM-S2)



Ceramics Depth measurement of a laser engraving (CCM-P1)



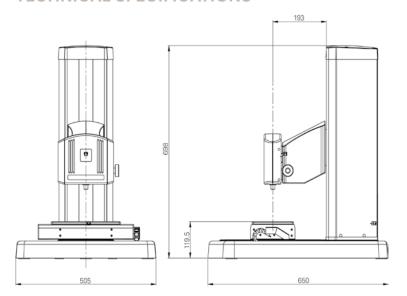
Abrasive Surface texture analysis of an industrial abrasive material (CCM P1)



Stylus tip Classical 2D internal roughness measurement (DIA P1)



TECHNICAL SPECIFICATIONS





DHM S2

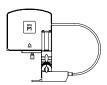
- DHM Technology
 Smooth surfaces, grinded or polished
 High precision and measurement speed



CCM P1

Chromatic Confocal Technology
• Rough surfaces, microforms

- Light-diffusing materials, plastics, biomaterials



DIA P1

- Diamond Stylus Tip Technology
 Classical roughness measurement
- Internal measurements

TR-SCAN

MEASURING HEADS

| | | DHM S2 | CCM P1 | DIA P1 |
|---|----|-------------|------------------------|------------|
| Technology | | DHM | Chromatic Confocal | Stylus tip |
| Vertical resolution (Z) | nm | 0.1 | 5 35 ²⁾ | 10 |
| Lateral resolution (XY) | μm | 0.6 | 1.1 4.0 ²⁾ | 1 |
| Typical max. measuring range Ra ¹⁾ | μm | 1 | 20 200 ²⁾ | 20 |
| Typical max. measuring range Rz1) | μm | 5 | 300 1100 ²⁾ | 200 |
| Max. permissible errors Ra | % | 1% | 1% 5% ²⁾ | 5% |
| Repeatability (Ra, 1σ) | nm | < 0.1 | <5 25 ²⁾ | 9 |
| Sample reflectivity | % | < 1% - 100% | 1% - 100% | - |
| Field of view | mm | 0.25 x 0.25 | - | - |

¹⁾ Values may differ depending on the surface texture 2) Objective dependent

INSTRUMENTS

| TR Scan | | 100 | 200 | 300 |
|------------------------------|----|-----|-----|-----|
| Horizontal measuring range X | mm | - | 100 | 100 |
| Horizontal measuring range Y | mm | - | - | 100 |
| Vertical measring range Z | mm | | 240 | |
| Meas. System resolution XYZ | μm | | 0.1 | |
| Positioning accuracy XYZ | μm | | 1 | |
| Max weight of the part | kg | | 20 | |







Instruments for Surface Measurement

TR PROFILE

Compact instrument for the measurement of roughness profiles (2D) Stylus with and without skid

TR PROFILE DH-7

Portable workshop instrument for the measurement of roughness profiles (2D) Stylus with and without skid

TR SCAN

CNC instrument for the measurement of roughness profiles (2D) and surfaces (3D) with and without contact

TRIMOS SAAv.de Longemalle 5 CH - 1020 Renens T. + 41 21 633 01 01 F. + 41 21 633 01 02 www.trimos.ch



TR SCAN PREMIUM



TR SCAN PREMIUM

INTRODUCTION

TR Scan Premium allows the measuring of the most sensitive surfaces with astounding speed and precision. It has become unavoidable in many cases for hi-tech applications, when the traditional measuring by contact has reached its limits. Medical appliances, prosthesis, wafers, MEMS, semiconductors, metallic layers deposits, polymer films, optical components, research and development, quality control, are the areas of expertise of TR Scan Premium.

The heart of the system, Trimos DHM® (Digital Holographic Microscopy), constitutes a derivation of a technology used in the biomedical engineering field. The system itself is based on the physical characteristics of the hologram for the topography generation of the analysed surface. This technology for checking industrial surfaces is exclusively used by Trimos. Its most distinctive feature to competitive products is the possibility of measuring extreme reflecting, mirror-polished or very small surfaces.

The exceptional high measuring speed coupled with an accuracy range of a nanometre form the main advantages of the TR Scan. Only some microseconds are needed for the acquisition of a three dimensional image (x, y, z) with a million points. This exceptional acquisition speed allows ignoring all problems traceable to vibrations, the traditional enemy of the majority of optical measuring systems. The mentioned advantages prove an enhanced productivity and a limited investment.

EXCEPTIONAL FAST MEASURING SPEED

INSENSITIVE TO VIBRATION

VERTICAL RESOLUTION IN NANOMETER RANGE

EXTREME SIMPLE POSITIONING OF THE PART THANKS TO LASER ALIGNMENT (DHM)

NON-CONTACT MEASURING, NON DESTRUCTIVE

SOFTWARE AT THE TOP OF THE TECHNOLOGY

PRE-PROGRAMMED MEASURING PROCESSES

COMPATIBLE WITH 2D AND 3D STANDARDS



DESCRIPTION

AUTOMATED Z-AXIS

The motorization of the axes allows entirely automatic measurements. The working distance is automatically given by the system. The measurement of surfaces wider than the field of vision of the lens is made possible thanks to a particularly efficient "stitching" function.



INTERCHANGEABLE MEASURING HEADS

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TR SCAN PREMIUM

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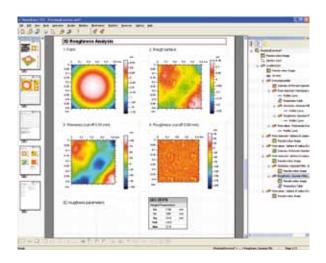
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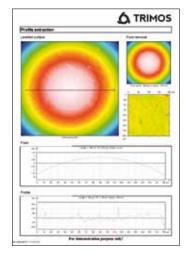
POWERFUL ANALYSIS

PROFESSIONAL REPORTING

SUITABLE MODULE FOR EACH APPLICATION NEED

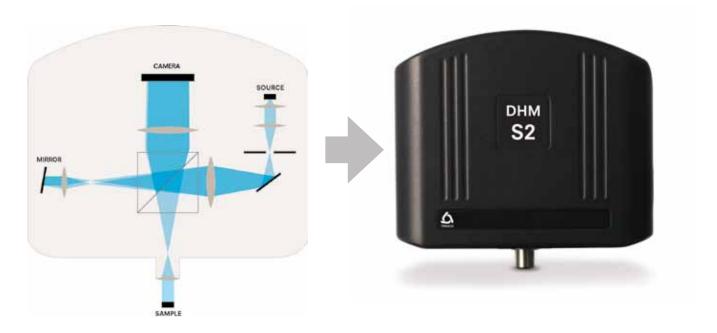
COMPLIES TO ALL INTERNATIONAL STANDARDS







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- Acquisition in a few microseconds
- Vibration incensitive
- High image quality
- Subnanometric resolution
- No moving parts
- No requirement for special environmental conditions

DHM is a recognized surface texture measurement method according to the standard ISO 25178-6

TR SCAN PREMIUM

MEASURING HEADS

DHM S1 & S2

DHM Technology:

- Smooth, grinded and polished surfaces
- Steel, aluminum, titanium, silicon, gold, ceramics, glass
- High precision and speed, 2D/3D

CCM P1

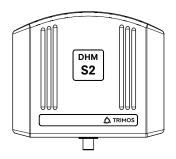
Chromatic Confocal Technology:

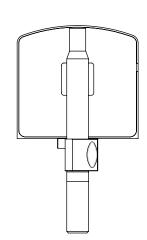
- Machined and rough surfaces, micro-structures
- Metals, plastics, abrasives, papers, textiles, cosmetics
- Large vertical range, all materials, 2D/3D

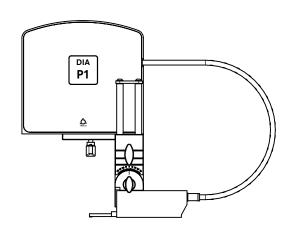
DIA P1

Diamond Stylus Tip Technology:

- Roughness measurement with contact
- Classical roughness measurements (2D)
- Internal measurements







TECHNICAL SPECIFICATIONS

| TR Scan Premium | | 101 | 301 | | |
|---------------------------------|----|-----|-----|--|--|
| Horizontal measuring range X | mm | - | 100 | | |
| Horizontal measuring range Y | mm | - | 100 | | |
| Vertical measuring range Z | mm | 240 | | | |
| Measuring system resolution XYZ | μm | 0.1 | | | |
| Positioning accuracy XYZ | μm | | 1 | | |
| Rectitude of the guideways XY | μm | 0 | .3 | | |
| Max weight of the part | kg | 20 | | | |

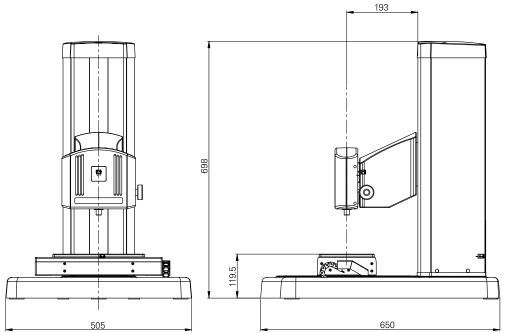
| Measuring Heads | | DHM S1 | DHM S2 | CCM P1 | DIA P1 |
|--|----|-------------|-------------|-------------------------|--------|
| Vertical resolution (Z) | nm | 0.1 | 0.1 | 8 ÷ 780 ²⁾ | 10 |
| Lateral resolution (XY) | μm | 0.6 | 0.6 | $0.9 \div 14^{2)}$ | 1 |
| Typical measuring range Ra ¹⁾ | μm | 0.4 | 1.6 | $0.012 \div > 200^{2)}$ | 20 |
| Vertical measuring range 1) | μm | 3 | 7 | 130 ÷ 24000 ²) | 350 |
| Max. permissible errors Ra | % | 1% | 1% | 1% ÷ 5% ²⁾ | 5% |
| Repeatability (Ra, 1 ₀) | nm | < 0.1 | < 0.1 | $<5 \div 25^{2}$ | 9 |
| Sample reflectivity | % | < 1% ÷ 100% | < 1% ÷ 100% | 1% ÷ 100% | - |
| Field of view | mm | 0.25 x 0.25 | 0.25 X 0.25 | - | - |

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DIAGRAM



STANDARD INSTRUMENT

The TR Scan Premium instruments are supplied as follows:

Instrument according to specification (without measuring head)

1 measuring head (DHM S1, DHM S2, CCM P1+TA-MI-701 ÷ 713)

PC with 1 TFT screen

Nanoware Measure and Nanoware Analysis softwares (according to selected model)

User's manual (750 50 0028 03)

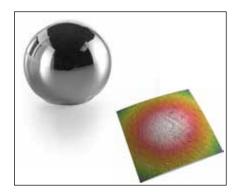
CODE NUMBER

| TR Scan Premium | Purpose | Meas. head | Axes | Software |
|---------------------------------|----------------------------------|------------|--|-------------------------------|
| TRSP101DHM 700 405 10 11 | 3D Measurement of tiny parts | DHM S2 | - 1 vertical axis Z | Nanoware STT (2D/3D analysis) |
| TRSP301DHM 700 405 30 21 | 3D measurement of metallic parts | DHM S2 | 1 vertical axis Z2 horizontal axes XY | Nanoware STT (2D/3D analysis) |
| TRSP301CCM 700 405 30 31 | Universal 3D measurements | CCM P1 | - 1 vertical axis Z 2 horizontal axes XY | Nanoware STT (2D/3D analysis) |

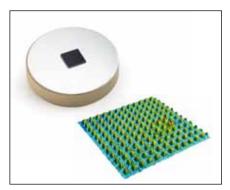
TR Scan Premium can also be specifically equipped according to each application need (head(s) and measuring table, software). An exhaustive list of equipments can be found in the accessories section.

TR SCAN PREMIUM

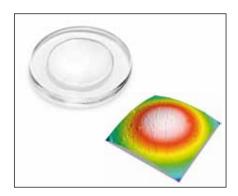
APPLICATIONS



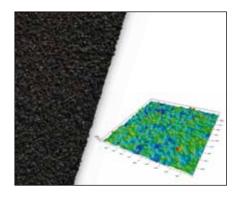
Quality control of a cobalt-chromium polished prosthesis surface (DHM-S2)



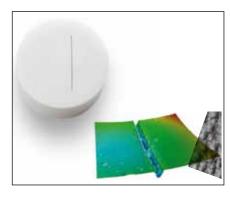
Analysis of a silicon microstructure (DHM S2)



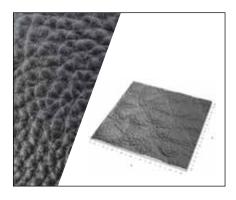
Roughness inspection of micro lenses (DHM S2)



Surface texture analysis of an industrial abrasive material (CCM P1)



Depth measurement of a laser engraving on ceramics (CCM-P1)



Topographic analysis of a leatherette sample (CCM-P1)



Measurment of macroscopic surface textures (CCM P1)



ISSOKU

ACCESSORIES

TR Profile VH
TR Profile VHF
TR Profile DH-8 VH
TR Profile DH-8 VHF
TR Scan

| • | | |
|---|--|--|
| | | |

| | | 꿑 | TR. | TR | TR | TR | TR S |
|---------------------------------|---|---|-----|----|----|----|------|
| TA-MI-701 279 970000 001 | Optical pen, with optical fiber and certificate, measuring range=130 µm, lateral resolution=0.9 µm | | | | | • | • |
| TA-MI-707 279 970001 001 | Optical pen, with optical fiber and certificate, measuring range=130 µm, lateral resolution=1.4 µm | | | | | • | • |
| TA-MI-708 279 970001 002 | Optical pen, with optical fiber and certificate, measuring range=400 μ m, lateral resolution=1.2 μ m | | | | | • | • |
| TA-MI-702 279 970000 002 | Optical pen, with optical fiber and certificate, measuring range=400 μ m, lateral resolution=1.7 μ m | | | | | • | • |
| TA-MI-713 279 970002 002 | Optical pen, with optical fiber and certificate, measuring range=400 μ m, lateral resolution=3.5 μ m | | | | | • | • |
| TA-MI-709 279 970001 003 | Optical pen, with optical fiber and certificate, measuring range=1400 μ m, lateral resolution=2 μ m | | | | | | • |
| TA-MI-703 279 970000 003 | Optical pen, with optical fiber and certificate, measuring range=1400 μ m, lateral resolution=4 μ m | | | | | | • |
| TA-MI-710 279 970001 004 | Optical pen, with optical fiber and certificate, measuring range=4000 μ m, lateral resolution=4 μ m | | | | | | • |
| TA-MI-704 279 970000 004 | Optical pen, with optical fiber and certificate, measuring range=4000 μ m, lateral resolution=7 μ m | | | | | | • |
| TA-MI-711 279 970001 005 | Optical pen, with optical fiber and certificate, measuring range=12000 µm, lateral resolution=7 µm | | | | | | • |
| TA-MI-705 279 970000 005 | Optical pen, with optical fiber and certificate, measuring range=124000 µm, lateral resolution=12.37 µm | | | | | | • |
| TA-MI-712 279 970001 006 | Optical pen, with optical fiber and certificate, measuring range=24000 µm, lateral resolution=8 µm | | | | | | • |
| TA-MI-706 279 970000 006 | Optical pen, with optical fiber and certificate, measuring range=24000 μ m, lateral resolution=14 μ m | | | | | | • |
| TA-MS-601 279 980001 001 | Standard tracer, with skid R = 25 mm bore $> \emptyset$ 8 mm, depth $<$ 27 mm | • | • | • | • | | |





TR Profile VH











TR Profile DH-8 VH

TR Profile DH-8 VHF

TR Scan

TR Scan Premium

ACCESSORIES

#1

IR Profile DH-8 VH FR Profile DH-8 VHF TR Scan Premium **IR Profile VHF TR Profile VH IR Scan TA-MS-602** Probe for small axes, knives, edges and wires 279 980001 002 with skid R=25 mm **TA-MS-603** Probe for small axes, knives, edges and wires without skid 279 980001 003 **TA-MS-604** Bore probe with skid R=10 mm bore $> \emptyset 2.5$ mm, depth < 20 mm 279 980002 001 Bore probe, without skid **TA-MS-605** 279 980002 002 bore $>\emptyset$ 1.5 mm, depth < 12 mm **TA-MS-606** Small bore probe, without skid 14 bore $> \emptyset 0.8$ mm, depth < 12 mm 279 980002 003 **1**% **TA-MS-607** Concave-convex probe, with skid R=1 mm 279 980003 001 for concave & convex workpieces with R>5 mm **TA-MS-608** Probe for slots, with skid R=25 mm 279 980004 001 slot depth < 15 mm, slot width > 3 mm **TA-MS-612** Probe for slots, H=5 mm, without skid 279 980004 005 slot depth < 5 mm, slot width > 1.0 mm TA-MS-611 Probe for slots, H=10 mm, without skid 279 980004 004 slot depth < 10 mm, slot width > 1.0 mm Probe for slots, H=15 mm, without skid TA-MS-609 279 980004 002 slot depth < 15 mm, slot width > 1.5 mm TA-MS-610 Probe for slots, H=20 mm, without skid slot depth < 20 mm, slot width > 1.5 mm 279 980004 003 10.0 **TA-MS-620** Probe for gear tooth profiles, with skid, 279 980005 001 module >= 2TA-MS-621 Probe for circumference and balls, with skid 279 980006 001 for $\emptyset >= 6 \text{ mm}$ TA-MS-622 Transverse probe, with skid R=25 mm 279 980007 001 **TA-MS-623** Transverse probe for slots, with skid R=1 mm 279 980007 002 slot depth < 7 mm



ACCESSORIES

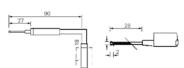
TR Profile DH-8 VH **IR Profile VHF**

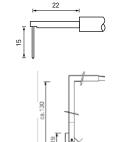
TR Profile VH

TR Scan



IR Scan Premium





| 279 980007 003 | with skid R=25 mm | |
|---------------------------------|--|---|
| TA-MS-626 279 980007 004 | Transverse probe left side, without skid | |
| TA-MS-627 279 980007 005 | Transverse probe right side, without skid | |
| TA-MS-625 279 980008 001 | Depth measuring probe, with skid R=25mm depth < 130 mm | • |
| TA-AD-601 | Extension 100 mm for probe | • |

Transverse probe for bores,





TA-AD-602

279 980901 002

279 980901 001

TA-MS-624



Extension 150 mm for probe





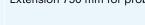


Extension 500 mm for probe



TA-MS-650

279 980010 001



Measuring head DHM S1

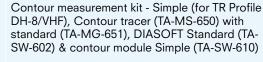
Contour tracer



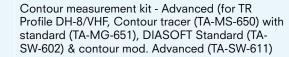


| TA-MS-651 |
|----------------|
| 279 980010 002 |











| DHM-S1 |
|------------|
| 709 70 001 |



| DHM-S2 | Measuring head DHM S2 |
|--------|-----------------------|



TR Profile VH



TR Profile VHF







TR Profile TR Scan
DH-8 VHF



TR Scan Premium

ACCESSORIES

IR Profile DH-8 VH TR Profile DH-8 VHF TR Scan Premium TR Profile VHF **IR Profile VH** CCM-P1 Measuring head CCM P1 709 70 005 DIA-P1 Measuring head DIA P1 709 70 003 TA-SU-601 XY table, base plate 70 x 70 mm, 279 981001 001 travel range 25 x 25 mm TA-SU-602 Vice for XY table TA-SU-601, opening 22mm 279 981901 001 **TA-AD-606** Measuring stand with drive unit holder 279 982001 001 with aluminium base and column H=250 mm TA-AD-608 Measuring stand with drive unit holder 279 982001 003 with aluminium base and column H=500 mm TA-AD-607 Measuring stand with drive unit holder with granite base and column H=250 mm 279 982001 002 TA-AD-610 Measuring stand with drive unit holder 279 982001 004 with granite base and column H=500 mm TA-AD-609 Drive unit holder 279 982901 001 TA-SU-603 Set with measuring stand and XY meas. table TA-AD-606 and TA-SU-601 279 989001 001 TA-SU-604 Set with measuring stand, XY meas. table and vice TA-SU-603 and TA-SU-602 279 989001 002 TA-SU-605 Swivelling stand, with magnetic base 297 700003 001 TA-SU-606 Precision vice 15 x 15 x 50 mm 297 700004 001 TA-SU-607 Precision vice 25 x 25 x 75 mm 297 700004 002 **TA-SU-608** Precision vice 35 x 35 x 100 mm 297 700004 003





ACCESSORIES

| ESSORIES | | | TR Profile VH | TR Profile VHF | TR Profile DH-8 VH | TR Profile DH-8 VHF | TR Scan | TR Scan Premium |
|--|---------------------------------|---|---------------|----------------|--------------------|---------------------|---------|-----------------|
| | TA-SU-609 297 700005 001 | Support plate for vice TA-SU-606 | • | • | • | • | • | • |
| | TA-SU-610 297 700005 002 | Support plate for vice TA-SU-607 | • | • | • | • | • | • |
| | TA-SU-611 297 700005 003 | Support plate for vice TA-SU-608 | • | • | • | • | • | • |
| | TA-SE-601 605 01 021 | Clamping set, TA-SU-605/TA-SU-607/TA-SU-610 | • | • | • | • | • | • |
| | TA-MG-609 278 980001 001 | Roughness standard, Ra=3.0 μm | • | • | • | • | • | • |
| | TA-MG-610 278 980001 002 | Roughness standard, Ra=3.0 μm, with SCS certificate | • | • | • | • | • | • |
| | TA-MG-611 278 980001 003 | Roughness standard, Ra=1.0 µm | • | • | • | • | • | • |
| | TA-MG-612 278 980001 004 | Roughness standard, Ra=1.0 µm, with SCS certificate | • | • | • | • | • | • |
| | TA-MG-601 278 980010 001 | Roughness standard Ra=25 nm, with DKD Certificate | | | | | • | • |
| | TA-MG-602 278 980010 002 | Roughness standard Ra=50 nm, with DKD Certificate | | | | | • | • |
| THE PARTY OF THE P | TA-MG-603 278 980010 003 | Roughness standard Ra=80 nm, with DKD Certificate | | | | | • | • |
| | TA-MG-605 278 980010 005 | Roughness standard Ra=0.2 μ m, with DKD Certificate | • | • | • | • | • | • |
| | TA-MG-606 278 980010 006 | Roughness standard Ra=0.5 μ m, with DKD Certificate | • | • | • | • | • | • |
| | TA-MG-607 278 980010 007 | Roughness standard Ra=1.5 μ m, with DKD Certificate | • | • | • | • | • | • |
| | TA-MG-604 278 980010 004 | Set of roughness standards Ra=25/50/80 nm with DKD Certificate | | | | | • | • |
| FILE | TA-MG-608 278 980010 008 | Set of roughness standards Ra=0.2/0.5/1.5 μm with DKD Certificate | • | • | • | • | • | • |
| Town or the same | TA-MG-651 278 980001 011 | Contour standard | • | • | • | • | • | • |
| 1 | TA-MG-652 278 980001 012 | Contour standard, with SCS certificate | • | • | • | • | • | • |
| | TA-EL-040 358 0020 | Joystick | | | | | • | • |







TR Profile VHF



TR Profile DH-8 VH



TR Profile DH-8 VHF



TR Scan



TR Scan Premium

ACCESSORIES

| VH ESS(| TR Profile VHF | TR Profile DH-8 VH | TR Profile DH-8 VHF | TR Scan | TR Scan Premium | TR Profile VH | TR Profile VHF | TR Profile DH-8 VH | TR Profile DH-8 VHF | <u>=</u> | TR Scan Premium |
|------------|----------------|-------------------------------|-------------------------------|---|---|---------------|----------------|---------------------------|---------------------|----------|-----------------|
| | | | | | | TR Pro | TR Pro | TR Pro | TR Pro | TR Scan | TR Sca |
| | | LABC-40 356 0010 | Laser printer (| USB) | | | | | | • | • |
| | | TA-EL-030 356 0016 | Inkjet printer (| USB) | | | | | | • | • |
| , | | TA-EL-001 332 10 0011 | Power cable, 2 | ower cable, 2 poles, Europe | | | | | | • | • |
| | - Marian | TA-EL-002 332 10 0013 | Power cable, 2 | 2 poles, USA/Ja | pan | | | | | • | • |
| | - | TA-EL-003 332 10 0016 | Power cable, 2 | 2 poles, Australia | a | | | | | • | • |
| | - | TA-EL-004 332 10 0014 | Power cable, 2 | 2 poles, UK | | | | | | • | • |
| _ | | TA-EL-005 616 20 003 | Power cable, 2 | 2 poles, Korea | | | | | | • | • |
| DIAS | | TA-SW-601 394 1 3301 | roughness and | | defined protocol, Ra, Rq, Rv, Rp, Rt, RDq, RPc) | • | • | • | • | | |
| | | TA-SW-602 394 1 3302 | + individual pr | SOFT Standard, otocols, zoom, s rison, (RLq, Rlo, | • | • | • | • | • | | |
| | ASOFT | TA-SW-603 394 1 3303 | SW-602 + add | | ve , Same as TA- O 12085 (CNOMO), x) | • | • | • | • | | |
| | | TA-SW-604 394 1 3304 | | SOFT Expert. Thoughness measu | e most complete urement | • | • | • | • | | |
| | | TA-SW-610 394 1 3310 | Module DIASO (for TA-SW-60 | OFT Contour Sii 2/603/604) | mple | | | | • | | |
| | | TA-SW-611 394 1 3311 | Module DIASO (for TA-SW-60 | OFT Contour Ac 2/603/604) | Ivanced | | | | • | | |
| | | TA-SW-612 394 1 3312 | Module DIASO (for TA-SW-60 | OFT Statistics (r 2/603/604) | oughness) | • | • | • | • | | |
| | | Nanoware LT 616 60 010 | | ofile analysis Na rement 2D - Basi | | | | | | • | • |
| | | Nanoware XT 616 60 011 | | ofile analysis Na rements 2D - Ad | | | | | | • | • |
| ı | VanoWare | Nanoware STT 616 60 012 | | ofile and surface T, 3D roughness | e analysis s Software - Basic | | | | | • | • |

Nanoware XTT Module for profile and surface analysis

Nanoware XTT, Roughness software 3D - Advanced

Complete module for profiles and surfaces Nano-Ware PRO, Roughness software 3D - Professional



616 60 013

616 60 014

Nanoware PRO